PFM-T800

Temperature Variation Test Report

Report NO: 07E020023

Issued by:	Rex Chang	/	*05/28/2007*
	Test Engineer		**Date**
Reviewed by:	Wenyuan Yang	/	*05/28/2007*
	Manager		**Date**

Test item list

Test Product: PFM-T800 A1.0 + PFM-620S A1.0

Sample Configuration & Quantity Under Test:

a. Test I/O Board: PFM-T800 A1.0

1. ISA Bridge Chipset: ITE 8888F
2. COM Chipset: Fintek F1216DG, four COM Ports.
3. USB Chipset: VIA VT6212, four USB Ports.

b. CPU Board: PFM-620S

1. CPU: Onboard Intel ULV Celeron 650MHz CPU (Bios Ver.1.0)
2. Memory: DSL 512MB / 0624PR V54C3256804VDJ7 / PC-133

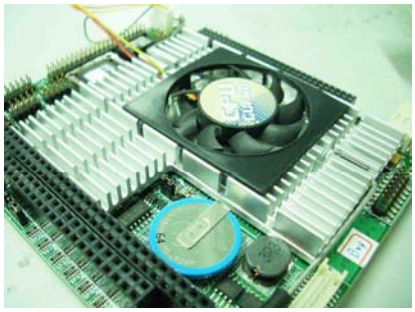
c. HDD: Seagate ST340015AGB

d. Test Software: Windows XP / Run PassMark Burn In Test V5.1 Pro

e. Test Item: COM Port and USB Port

f. AT Power Supply: Zippy SP2-4300F

g. CPU Cooler:



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Temperature variation operation test

Test Date: 05-24~25-2007

Test Site: AAEON QA Internal Lab.

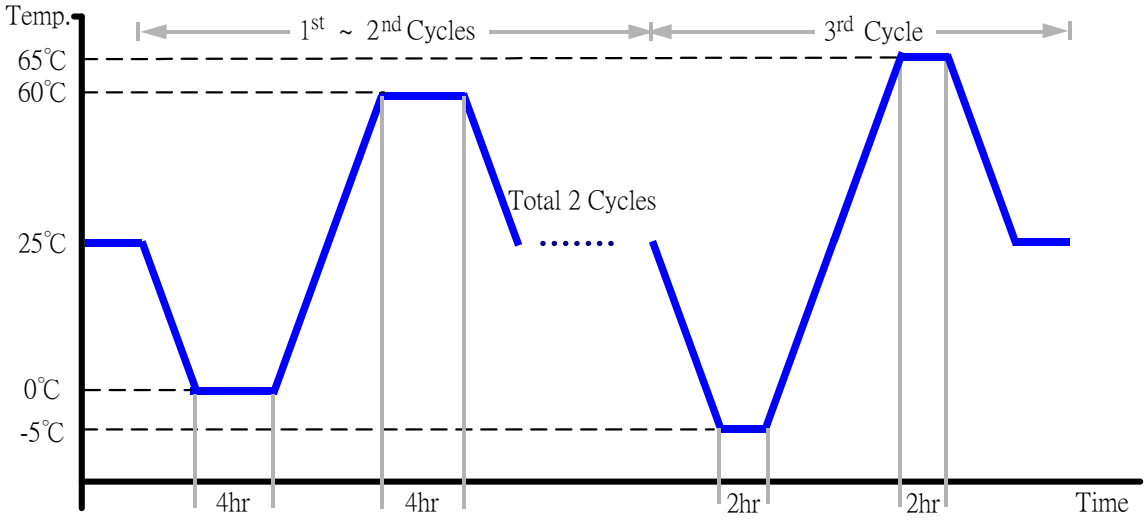
Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-A4C-100
Date of Calibration: 07/07/06
Serial Number: 3188

Temperature & Humidity Cycle Test:

1. Test Low Temperature: 0℃ (1~2 cycles)
   -5℃ (3rd cycle)
2. Test High Temperature: 60℃ (1~3 cycles)
   65℃ (3rd cycle)
3. Test dwell time: 4Hrs (1~2 cycles)
   2Hrs (3rd cycle)
4. Temperature slope: 2℃/min
5. Test cycle: 3 cycles
6. Test Environment Curve:



Test Result:

No problem was found during the Temperature & Humidity Cycle Test.

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